

Image 2829

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(Case No. 219.003-US)

In the Application of: **Yamada**

Serial No: **09/865,528**

Filed: **May 29, 2001**

Title: **Semiconductor Device Test Method and
Semiconductor Device Tester**

)
) Group
) Art Unit: **2829**
)
) Before
) Examiner: **V. Nguyen**
)
)

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

FEE TRANSMITTAL

Dear Sir:

Transmitted herewith is an **Information Disclosure Statement** (1 page + Form PTO-1449 (3 sheets) and references cited therein.

The fee has been calculated as shown below:

CLAIMS AS AMENDED						
	Claims Remaining	Highest Number Previously Paid	Extra	Rate		Amount
				Large	Small	
Number of Claims In (in excess of 20)	0	0	0	\$18.00	\$9.00	-0-
Independent Claims (in excess of 3)	0	0	0	\$84.00	\$42.00	-0-
Extension Fee: a) One Month				\$110.00	\$55.00	-0-
Filing of Information Disclosure Statement (37 C.F.R. §1.17(p)):						\$180.00
TOTAL FEE DUE:						\$180.00

Method of Payment:

☒ [XX] A check payable to the Commissioner of Patents and Trademarks, in the amount of \$180.00 is enclosed as payment of the Total Fee.

☐ [] Please charge my Deposit Acc. 50-0763 in the amount of \$_____ to cover the above fees. A duplicate copy of this sheet is enclosed.

☒ [XX] The Commissioner is hereby authorized to charge any fees that may be required, or credit any overpayment to Deposit Acc. 50-0763. A duplicate copy of this sheet is enclosed.

Date: March 17, 2004

Respectfully submitted,

Neil Steinberg, Reg. No. 34,735
Telephone No. (650) 968-8079



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INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Submitted herewith are three (3) sheets of a modified Form PTO-1449. A copy of each document cited on the attached Form PTO-1449 is also submitted.

Notably, most of the documents listed on the attached Form PTO-1449 were identified and/or cited in applications (namely, U.S. App. Serial Nos. 09/451,440 and 09/702,831) that include subject matter which is similar to that in the above-reference application.

It is respectfully requested that the Examiner make his/her consideration of these documents formally of record with the initial Office Action.

Respectfully submitted,

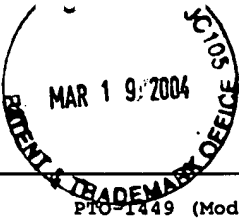
Neil A. Steinberg, Reg. No. 34,735
650-968-8079

Date: March 17, 2004

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PTO-1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. 219.003-US	SERIAL NUMBER 09/865,528
	APPLICANT(S) Yamada	
	FILING DATE May 29, 2001	GROUP ART UNIT 2829

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
	4,988,877	1/1991	Stokowksi et al.			
	4,949,162	8/1990	Tamaki et al.			
	5,001,536	3/1991	Fukuzawa et al.			
	5,327,012	7/1994	Yano et al.			
	5,412,210	5/1995	Todokoro et al.			
	5,637,186	6/1997	Liu et al.			
	5,780,870	7/1998	Maeda et al.			

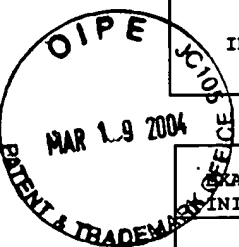
FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO
	6-273297	9/1994	Japan			
	7-66172	3/1995	Japan			
	57-6310	1/1996	Japan			
	8-313244	11/1996	Japan			
	9-61142	3/1997	Japan			
	10-300450	11/1998	Japan			
	50-63990	5/1975	Japan			
	62-19707	1/1987	Japan			
	8-5528	1/1996	Japan			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	DATE CONSIDERED
EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication to applicant.	

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	APPLICANT(S)	
	Yamada	
	FILING DATE	GROUP ART UNIT
	May 29, 2001	2829



U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
	5,900,645	5/1999	Yamada			
	6,037,588	3/2000	Liu et al.			
	6,127,193	10/2000	Bang et al.			
	6,317,514	11/2001	Reinhorn et al.			
	5,280,176	1/1994	Jach et al.			
	5,089,774	2/1992	Nakano			
	5,132,507	7/1992	Nakano			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO
	3-205573	9/1991	Japan			
	4-62857	2/1992	Japan			
	10-281746	10/1998	Japan			
	11-26343	1/1999	Japan			
	2000-164715	6/2000	Japan			
	2000-180143	6/2000	Japan			
	2000-124276	4/2000	Japan			
	2000-174077	6/2000	Japan			
	62-19707	1/1987	Japan			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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PTO-1449 (Modified)

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PATENT AND TRADEMARK OFFICEINFORMATION DISCLOSURE STATEMENT
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EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
	6,169,603	1/2001	Takayama			
	6,141,038	10/2000	Young et al.			
	6,078,386	6/2000	Tsai et al.			
	6,052,478	4/2000	Wihl et al.			
	5,717,204	2/1998	Meisburger et al.			
	5,578,821	11/1996	Meisberger et al.			

FOREIGN PATENT DOCUMENTS

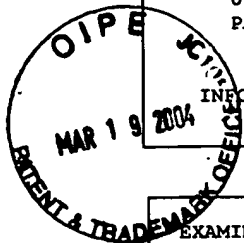
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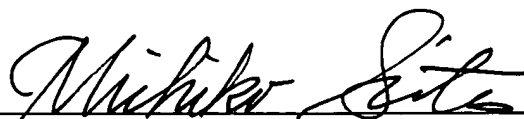
Commissioner for Patents
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Alexandria, VA 22313-1450

Certificate of Mailing under 37 CFR 1.8

I hereby certify that the attached: **(1)** Information Disclosure Statement (1 page + Modified PTO-1449 (3 sheets) and References cited therein); **(2)** Fee Transmittal (1 page + 1 copy thereof); **(3)** Check (\$180.00) are being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to:

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

on March 17, 2004.



Signature



Print Name of Person Signing Certificate